

RESOLVABILITY OF THE STARPHENE STRUCTURE AND APPLICATIONS IN ELECTRONICS

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Abstract:

Polycyclic aromatic hydrocarbons, or starphenes, are composed of three distinct acene-arm variants. The fundamental building blocks for the downsizing of various electronic devices, particularly organic ones, are starphenes. It was also a key component of several logical gates. Every electrical circuit, structure, or network in network topology can be represented as a graph with line segments (branches) acting as edges and primary nodes (or simply nodes) alternating to vertices. Resolvability parameters of a graph are a relatively recent specialized field in which the unique location of each primary node is obtained by forming the network as a whole. This article investigates the metric, edge metric dimension, and generalizations as resolvability characteristics of starphene structure. We demonstrated the consistent cardinalities of all the parameters examined for the starphene graph. Transforming the entire structure into a fresh shape provided by resolvability parameters facilitates understanding and handling of structures.

1. Introduction

The graphical representation of electric circuits known as network topology. Complex and complicated electric circuits or networks are relatively not easy to work on and study in their original forms, to make them easy and understandable, network topology is used. Any electric circuit or network can be transformed or shaped into its equivalent graph, in this procedure of terraforming an electric network into graph, open circuits took places of current sources and short circuits are came up in place of the passive elements and voltage sources. Open circuits usually denoted by nodes (or principal nodes) in network topology and vertices in pure mathematical graph theory, whereas short circuits are called as line segments (or branches) in network topology and edges in graph theory conceptualization. The formal definition of graphical representation of an electric circuit or network is defined as:

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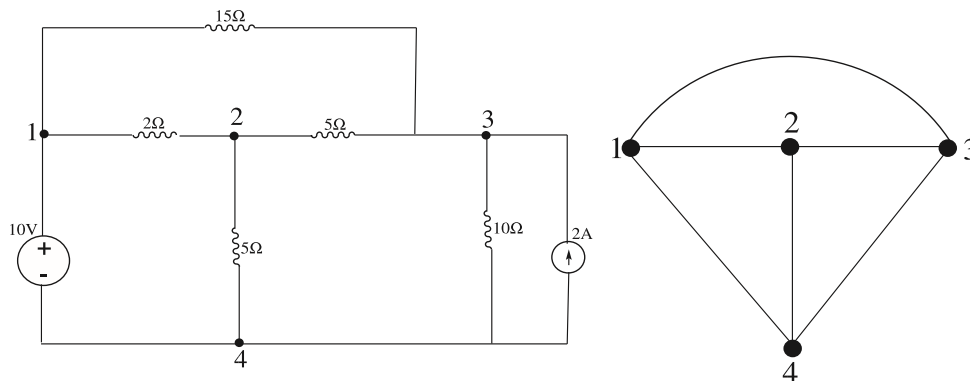
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Peer review under responsibility of Ain Shams University. Definition 1.1 [25]. “Let $G = (V, E)$ is an electric circuit (network) with V is called as set of principal nodes (vertex set) and E is the set of branches (edge set). The total number of principal nodes in an electric network are $|V|$ and the count of branches usually denoted as $|E|$, basically these are order and size of a equivalent graph of an electric network.”

To elaborate more in depth we took an example to transform an electric circuit into its corresponding graph. In the circuit shown in Fig. 1 (left), the labeling with 1; 2; 3, and 4, we can see are the four principal nodes (or vertices). There are also labeling with 15 X; 2 X; 5 X; 5 X, and 10 X are the resistors having resistances in X-unit, 2 A is a current source, 10 V

which is a voltage source, these are all seven branches (or edges) in the above circuit. There is another drawing shown in the following Fig. 1 (right), which is an equivalent graph of the electric circuit. For more detail of transformation of a electric circuit to graph see [53].

We will show some technique of graph to demonstrate theoretical parameters in the context of electronics. There are several different approaches to examine and investigate circuits of electric when it comes to graph theory. In 1975, [50,13] presented an effective notion of network visualization; in this concept, a small number of main nodes are chosen so that the whole set of principle nodes can be identified in relating to a distance vector, this is referred to as the metric basis or resolving set. This notion laid the groundwork for a number of graph theoretical parameters that are used in a variety of electrical and chemical engineering,



and in other areas. The fault-tolerant concept of the definition of resolving set, described by [5], is also a unique approach of examining a graph (structure) wherein fault-tolerant of a solemn main vertex from the resolving set may be allow while the full collection of primary vertices still has a unique location. In 2018, [21] developed the edge metric resolving set, which assigns a unique location to the whole set of branches (edges) instead of main nodes. The authors in [28], investigated the edge version of a fault-tolerant resolving set in 2020. In [22], authors presented the combination version of resolving and edge metric resolving set in 2017, which allows whole sets of main nodes and branches to be uniquely identified. Partition resolving set [6] is created when the whole set of primary vertices, is split down into subgroups and the requirement of acquiring distinct position of the set of principal nodes is met. All of the aforementioned ideas are referred to be metric-based resolvability parameters, and they've been investigated for many circuits, networks and graphs. For more versions of graph theoretical aspects, we refer to see [11,12,41].

The researchers of [14,27,7,6], examined complexity or computational cost and demonstrated that all of the parameters from resolvability family, investigated in this work relate to the nondeterministic polynomial time-hardness. The investigators are inspired by the proven results of the metric dimension which has a wide range of practical applications in our everyday lives and is well-studied. Metric dimension is used in a variety of disciplines, including the weighing of coins [50], robot navigation [23], pharmaceutical chemistry [7], computer networks [30,46] also linked to this idea, coastguard loran, sonar, and facility locating difficulties connected to this concept in the foundational article by [49], for a more comprehensive examination and the uses of this pointer [35,36]. In several real-world applications, the partition dimension is also described, as an illustration, by [4], the process of identifying a network and also its verification is connected to this idea, the piloting or

elements in the subset R is actually the metric dimension of $@$ and it is denoted by the term $\dim \delta P@$.

Definition 1.4 ([5,25]). "A particular chosen ordered subset which were actually resolving set symbolize by R of a network $@$ is considered to be a fault-tolerant denoted by $\delta Rf P$, now if for each member of $f \in R$, with the condition $R \setminus f$ is also remain a resolving set for the network $@$. The fault-tolerant metric dimension will be the least possible elements in the fault-tolerant resolving set and labeled as $\dim f \delta P@$."

Definition 1.5 ([21,24]). "A principal node $f \in V \delta P@$ and a branch $e \in E \delta P@$, the distance between f and e is defined as $d_{\delta e;fP} = \min \{d_{\delta f1;fP}, d_{\delta f2;fPg}\}$. Suppose $R_e \subseteq V \delta P@$ is the subset of principal nodes set and defined as $R_e = \{f1;f2;...;fsg\}$, and a branch $e \in E \delta P@$. The identification $r_{\delta e;fP}$ of a branch e with respect to R_e is actually a s -tuple distances $\{d_{\delta e;f1P}, d_{\delta e;f2P};...; d_{\delta e;fsgP}\}$. If each branch from $E \delta P@$ have unique identification according to R_e , then R_e is called an edge metric resolving set of network $@$. The least possible elements in the set R_e is labeled as the edge metric dimension of $@$ and it is represented by $\dim e \delta P@$."

Definition 1.6 ([28,24]). "An fault-tolerant edge metric resolving set $\delta R_e;f P$ of a network $@$ is considered, if for each $f \in R_e$; $R_e \setminus f$ is remains an edge metric resolving set for $@$. The fault-tolerant edge metric dimension will be the minimum amount of members in the fault-tolerant edge metric resolving set and it is described as the entire set of principal nodes have unique identifications, then R_p is named as the partition resolving set of the principal node of a network $@$. The least possible count of the subsets in that set of $V \delta P@$ is labeled as the partition dimension $\delta p \delta P@$ of $@$."

Given below are some useful observations and are very necessary in the finding of our main results of the resolvability parameters of our graph $@$.

Theorem 1.9 [8]. Let $\dim \delta P@$, the metric and $\dim f \delta P@$ is the faulttolerant metric dimension of graph $@$. Then $\dim f \delta P@ \leq \dim \delta P@ \leq 1 + \dim e;f \delta P@$."

Definition 1.7 [22]. If the identifications of entire set of principal nodes and branches are unique with respect to a chosen resolving set $R_m \subseteq V \delta P@$, then R_m is called as mixed metric resolving set, and the minimum count of elements in R_m is called as mixed metric dimension and denoted as $\dim m \delta P@$.

Definition 1.8 ([6,24]). "Let $R_p \subseteq V \delta P@$ is the s -elements proper set and $r_{fjRp} = \{d_{\delta f;Rp1P}, d_{\delta f;Rp2P};...; d_{\delta f;RpsPg}\}$, is the s -tuple disp tance identification of a principal node f in association with R . If Theorem 1.12 [22]. Let $\dim m \delta P@$ be a mixed metric dimension of a graph $@$. Then $\dim m \delta P@ \leq \max \{ \dim \delta P@ ; \dim e \delta P@ \}$:

2. Construction of Starphene $St l \delta ;m;nP$

Starphenes are two-dimensional polycyclic aromatic hydrocarbons (PAH) which are build by three acene arms [33] connected systematically on a centered benzene ring [40]. Starphenes are widely used in many electronic devices, and played a key role in the revolution of miniaturization of electronic devices. The structure used in the single molecule electronics as NOR [44] and as well as NAND [43]. The starphenes are very attractive materials in different electronic applications, especially organic electronics, the starphenes behaved as a component which is organic light emitting diodes in the field effect transistors [20].

Starphenes are belongs to the family of PAH, it has three acene arms we denoted as $l; m; n$ arms on a centered benzene ring. We denote the starphene structure or network throughout the work as $St\ l\ ;\ m;\ n$. The total number of vertices in starphene with different $l; m$ and n variation $4\ l\ +\ m\ +\ n\ -\ 6$, and $5\ l\ +\ m\ +\ n\ -\ 9$ are the total nodes or line segments. Given below are the vertex (or principal nodes) and edge set (line segment or branches) of corresponding graph of $St\ l\ ;\ m;\ n$. Theorem 1.10 [28]. Let $dime\ P@$, the edge metric and $dime;f\ \delta\ P@$ is the fault-tolerant edge metric dimension of graph $@$. Then $dime;f\ \delta\ P@ \geq dime\ P@ + 1$:

Theorem 1.11 ([50,52]). Let $dim\ P@$; $dime\ P@$; $dimm\ P@$; $pd\ P@$, are the metric, edge metric dimension, mixed metric dimension and partition dimension of a graph $@$ respectively. Then

$dim\ P@ \leq dime\ P@ + 1$; iff $@$ is a path graph;

$dimm\ P@ \leq pd\ P@ + 1$; iff $@$ is a path graph:

Furthermore, by merging the vertex and edge sets of $St\ l\ ;\ m;\ n$ created above, the vertices marking utilized in the discoveries reported in Fig. 2, and the generalize $St\ l\ ;\ m;\ n$ can be constructed.

3. Results on the resolvability of starphene $St\ l\ ;\ m;\ n$

This section is started by the core of this work, in which the resolving set with cardinality two is chosen from the possible combinations, later it's generalizations in which the faulttolerant version of resolving set, edge metric dimension and its generalized version which same as the fault-tolerant of given above, mixed metric dimension and at the end final version of all resolvability parameters named as the partition dimension are elaborated.

Lemma 3.1. Let the graph of starphene is $St\ l\ ;\ m;\ n$ with $l; m; n \geq 2$. Then the cardinality of resolving set of $St\ l\ ;\ m;\ n$ is 2.

Proof. Let $R = \{a, b\}$, from the vertex set of graph of starphne $St\ l\ ;\ m;\ n$, with cardinality two. Consider R is one of the potential candidate for the role of resolving set. The identifications of the complete set of nodes in $St\ l\ ;\ m;\ n$ with regard to the nodes in R are provided below.

Theorem 3.4. If the graph of starphene is $St_{l\delta ; m ; n\mathbb{P}}$ with $l ; m ; n \in \mathbb{P}^2$, then $\dim_f \delta St_{l\delta ; m ; n\mathbb{P}} \geq 4$:

Proof. By using the basic technique of double inequality, to prove that the graph of starphene $St_{l\delta ; m ; n\mathbb{P}}$ has four fault-tolerant metric dimension. We refer to see the Lemma 3.3, in that proved we already showed that the potential candidate for the fault-tolerant resolving set $R_f \subseteq V$ with cardinality one time for each loop, resulted in the same identifications are; $r_{v_f} R_{0f} \neq r_{v_j} R_{0f}$, where $v_f, v_j \in V$ acenearmverticesg.

Case 3: Let $R_{0f} = \{f : f \in \{1, 2, \dots, 2\delta l \mid n - 1\mathbb{P}\}$, and containing three members one time for each loop, resulted in the same identifications are; $r_{v_f} R_{0f} \neq r_{v_j} R_{0f}$, where $v_f \in V$ acenearmverticesg, and $v_j \in V$ acenearmverticesg.

Case 4: Let $R_{0f} = \{f, b_j : f \in \{1, 2, \dots, 2\delta l \mid n - 1\mathbb{P}\}$; and $j \in \{1, 2, \dots, 2\delta l \mid m - 1\mathbb{P}\}$, and containing three members one time for each loop, resulted in the same identifications are; $r_{v_f} R_{0f} \neq r_{v_j} R_{0f}$, where $v_f, v_j \in V$ acenearmverticesg.

Case 5: Let $R_{0f} = \{f, c_j : f \in \{1, 2, \dots, 2\delta l \mid n - 1\mathbb{P}\}$; and $j \in \{1, 2, \dots, 2\delta m \mid n - 1\mathbb{P}\}$, and containing three members one time for each loop, resulted in the same identifications are; $r_{v_f} R_{0f} \neq r_{v_j} R_{0f}$, where $v_f, v_j \in V$ acenearmverticesg.

Case 6: Let $R_{0f} = \{f, b_j, c_j : f \in \{1, 2, \dots, 2\delta l \mid m - 1\mathbb{P}\}$; and $j \in \{1, 2, \dots, 2\delta m \mid n - 1\mathbb{P}\}$, and containing three members one time for each loop, resulted in the same identifications are; $r_{v_f} R_{0f} \neq r_{v_j} R_{0f}$, where $v_f \in V$ acenearmverticesg, and $v_j \in V$ acenearmverticesg.

All the above chosen cases are resulted in that there is no candidate for fault-tolerant resolving set with cardinality three and implied that the graph does not have $\dim_f \delta St_{l\delta ; m ; n\mathbb{P}} \leq 3$. Hence; $\dim_f \delta St_{l\delta ; m ; n\mathbb{P}} \geq 4$.

Now by relating both inequalities, end up with conclusion that $\dim_f \delta St_{l\delta ; m ; n\mathbb{P}} \geq 4$:

Lemma 3.5. Let the graph of starphene is $St_{l\delta ; m ; n\mathbb{P}}$ with $l ; m ; n \in \mathbb{P}^2$. Then the cardinality of edge metric resolving set of $St_{l\delta ; m ; n\mathbb{P}}$ is 3.

$\delta \in \{1, 2\delta l \mid n\mathbb{P} - 3\mathbb{P} ; 2\delta l \mid m - 1\mathbb{P} - f\mathbb{P} ;$

$r_{a\delta} \{f, b_j, c_j\} \subseteq V$ $\delta \in \{1, 2\delta l \mid n\mathbb{P} - 3\mathbb{P} ; 2\delta m - 1\mathbb{P} \mid 1\mathbb{P} - f\mathbb{P} ;$

$> : \text{ if } f \in \{1, 2, \dots, 2l - 2\} ; \text{ if } f \in \{1, 2, \dots, 2\delta l \mid n\mathbb{P} - 3\mathbb{P} ;$

Proof. Let $R_e \subseteq E$ with cardinality three. Consider R_e is one of the potential candidate for the role of edge resolving set. The identifications of the complete set of edges in $St_{l\delta ; m ; n\mathbb{P}}$ with regard to the nodes in R_e are provided below.

For $f \in \{1, 2, \dots, 2\delta l \mid n\mathbb{P} - 3\mathbb{P}$, the $r_{a\delta} \{f, b_j, c_j\}$, are following; For Case 4: Let $R_{0e} = \{f, b_j : f \in \{1, 2, \dots, 2\delta l \mid n - 1\mathbb{P}\}$; and $j \in \{1, 2, \dots, 2\delta l \mid m - 1\mathbb{P}\}$, the $r_{b_j} \{f, b_j, c_j\}$, are following; $1, 2, \dots, 2\delta l \mid m - 1\mathbb{P}$, and containing three members one time

$> \delta \delta f ; 2\delta l \mid m - 1\mathbb{P} - f\mathbb{P} ; 2\delta l \mid m - 3\mathbb{P} - f\mathbb{P} ; \text{ if } f \in \{1, 2, \dots, 2l - 2\} ;$
 $r_{b\delta} \{f, b_j, c_j\} \subseteq V < \delta f ; 2\delta n - 1\mathbb{P} \mid 1\mathbb{P} - f\mathbb{P} ; 2\delta l \mid m - 3\mathbb{P} - f\mathbb{P} ; \text{ if } f \in \{1, 2, \dots, 2l - 2\} ;$

\ggg : if $f \in \{1, 2, \dots, 2m\}$ then 3 :

For $f \in \{1, 3, 5, \dots, 2l - 1\}$, the $r \in \{f, f+1, f+2, \dots, f+l-1\}$ are given below; $r \in \{f, f+1, f+2, \dots, f+l-1\}$;

For $f \in \{2l, 2l+2, 2l+4, \dots, 2l+n-1\}$, and $j \in \{2l, 2l+2, \dots, 2l+n-1\}$, the $r \in \{f, f+1, f+2, \dots, f+l-1\}$ are given below; $r \in \{f, f+1, f+2, \dots, f+l-1\}$;

For $f \in \{2l, 2l+2, 2l+4, \dots, 2l+m-1\}$, and $j \in \{2n, 2n+2, \dots, 2m+n-1\}$, the $r \in \{f, f+1, f+2, \dots, f+l-1\}$ are given below; $r \in \{f, f+1, f+2, \dots, f+l-1\}$;

We can see that all the primary edges held unique identifications and met the idea of a edge fault-tolerant resolving set by concluding that $Re \in \{1, 2, 3, 4\}$, by looking at the identifications of the whole group of edges of $St(l, m; n)$.

Theorem 3.8. Let the graph of starphene is $St(l, m; n)$ with $l, m, n \geq 2$. Then $dim_e(St(l, m; n)) = 4$:

Proof. To show that the graph of starphene $St(l, m; n)$ has faulttolerant edge metric dimension 4, we are implementing the method of double inequality and implied at $dim_e(St(l, m; n)) = 4$, which is already proven by the Lemma 3.7, it proved that there is a candidate for the fault-tolerant edge metric resolving set with cardinality four, it is taken as $Re \in \{1, 2, 3, 4\}$.

Now for $dim_e(St(l, m; n)) \leq 4$, by contradiction we get $dim_e(St(l, m; n)) \leq 3$, and by referring the Theorem 1.10 and

Theorem 3.6 concluded that 3 fault-tolerant edge metric dimension of $St(l, m; n)$ is not possible. Hence; $dim_e(St(l, m; n)) = 4$.

Now by relating both acquired inequalities, end up on the conclusion that $dim_e(St(l, m; n)) = 4$:

Lemma 3.9. Let the graph of starphene is $St(l, m; n)$ with $l, m, n \geq 2$. Then the cardinality of mixed metric resolving set of $St(l, m; n)$ is 3.

For $f \in \{1, 2, \dots, 2l+m-1\}$, the $r \in \{f, f+1, f+2, \dots, f+l-1\}$ are following; $r \in \{f, f+1, f+2, \dots, f+l-1\}$;

For $f \in \{1, 2, \dots, 2m+n-1\}$, the $r \in \{f, f+1, f+2, \dots, f+l-1\}$ are following; $r \in \{f, f+1, f+2, \dots, f+l-1\}$;

The above identifications are just the nodes identifications, to fulfill the definition of mixed we need the identifications of entire line segment set as well, as we know that $Re \in \{1, 2, 3, 4\}$, mean that the cardinalities of both edge metric and mixed metric resolving sets are same, therefore, for the identifications of entire branches set we refer the Lemma 3.5.

We can see that all the primary edges and nodes as well held unique identifications and met the idea of a mixed resolving set by concluding that $j \in \{1, 2, 3\}$, by looking at the identifications of the whole group of edges and nodes of $St(l, m; n)$.

Theorem 3.10. Let the graph of starphene is $St(l, m; n)$ with $l, m, n \geq 2$. Then $dim_m(St(l, m; n)) = 3$:

Proof. To show that the graph of starphene $St_{l\delta; m; nP}$ has mixed metric dimension 3, by implementing the method of double inequality, and referring the Lemma 3.9 in which one of the candidate of mixed metric resolving set with cardinality 3 is given and it is taken as $R_m \frac{1}{4} fa_1; a_2\delta l_{pn}1P; b_2\delta l_{pm}1Pg$.

Now we will prove that $\dim_{\delta} St_{l\delta; m; nP} \geq 3$. On contrary we can see that the starphene is not a path graph (see Theorem 1.11) and using Theorem 1.12, it indicate that 2 mixed metric dimension of $St_{l\delta; m; nP}$ is not possible. Hence; $\dim_{\delta} St_{l\delta; m; nP} \geq 3$.

Hence,

$$\dim_{\delta} St_{l\delta; m; nP} = 3$$

Lemma 3.11. Let the graph of starphene is $St_{l\delta; m; nP}$ with $l; m; n \geq 2$. Then the cardinality of partition resolving set of $St_{l\delta; m; nP}$ is 3.

Proof. Let $R_p \frac{1}{4} fR_{p1}; R_{p2}; R_{p3}g$, where $R_{p1} \frac{1}{4} fa_1g; R_{p2} \frac{1}{4} fa_2\delta l_{pn}1Pg; R_{p3} \frac{1}{4} V St_{l\delta; m; nP} n fa_1; a_2\delta l_{pn}1Pg$, of the vertex set of graph of starphene $St_{l\delta; m; nP}$, with cardinality three. Consider R_p is one of the potential candidate for the role of partition resolving set. The identifications of the complete set of nodes in $St_{l\delta; m; nP}$ with regard to the nodes in R_p are provided below.

Table 1

Resolvability parameters of starphene $St_{l\delta; m; nP}$.

$$\dim St_{l\delta; m; nP} = 3 \quad \dim_{\delta} St_{l\delta; m; nP} = 3 \quad \dim_{\delta} St_{l\delta; m; nP} = 3 \quad \dim_{\delta} St_{l\delta; m; nP} = 3$$

For $f \frac{1}{4} 1; 2; \dots; 2\delta l_{pn} 1P$, the $r_a f_j R_p$, are following; $r_a f_j R_p \frac{1}{4} \delta f 1; 2\delta l_{pn} 1P f; zP$:

Where $z \frac{1}{4} 10;$ if otherwise $f \frac{1}{4} 1; 2\delta l_{pn} 1P; .$

For $f \frac{1}{4} 1; 2; \dots; 2\delta l_{pm} 1P$, the $r_b f_j R_p$, are following;

$r_b f_j R_p \frac{1}{4} \delta \delta f f; 2\delta \delta n l_{pn} 1P \frac{1}{4} 11 p f f; 00P; .$ if $f f \frac{1}{4} 211; 22; 1...p ; 12; 1...; 12; \delta l_{pm} p 1P$:

For $f \frac{1}{4} 1; 2; \dots; 2\delta m p n 1P$, the $r_c f_j R_p$, are following;

$r_c f_j R_p \frac{1}{4} \delta \delta 2\delta \delta n l_{pm} 1P \frac{1}{4} p 11 p f f; f; f; 0P0; P; .$ if $f f \frac{1}{4} 21m; 2; 2...m; p 2m 1; ...1; 2\delta m p n 1P$:

We can see that all the primary nodes as well held unique identifications and met the idea of a partition resolving set by concluding that $R_p \frac{1}{4} 3$, by looking at the identifications of the whole group of nodes of $St_{l\delta; m; nP}$. h

Theorem 3.12. Let the graph of starphene is $St_{l\delta; m; nP}$ with $l; m; n \geq 2$. Then $\dim St_{l\delta; m; nP} = 3$;

Proof. To show that $St_{l\delta; m; nP}$ has the partition dimension which is 3. From Lemma 3.11 given above shows that there is a candidate of the partition resolving set with cardinality 3 and it is been taken as, $R_p \frac{1}{4} fR_{p1}; R_{p2}; R_{p3}g$, where $R_{p1} \frac{1}{4} fa_1g; R_{p2} \frac{1}{4} fa_2\delta l_{pn}1Pg$, and $R_{p3} \frac{1}{4} V St_{l\delta; m; nP} n fa_1; a_2\delta l_{pn}1Pg$. By using Lemma 3.11 and Theorem 1.11, it is concluded that $\dim St_{l\delta; m; nP} = 3$;

4. Conclusion

This article examines the structure of the starphene $St_{l\delta; m; nP}$ in terms of various resolvability parameters, particularly those that depend on a graph's metric. The first of these

parameters is referred to as the metric dimension, and numerous generalizations are offered before arriving at the mixed metric dimension. Additionally, the partition dimension is a generalization of the original idea of resolvability parameters. Table 1 presents the conclusion observations based on the research work conducted.

Declaration of Competing Interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

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